L Number	Hits	Search Text	DB	Time stamp
17	285	((critical adj dimension adj electron adj microscop$2) (CD adj SEM) CDSEM CD-SEM)	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/08/06 13:11
18	47	(((critical adj dimension adj electron adj microscop$2) (CD adj SEM) CDSEM CD-SEM)) and ((tilt$3 angl$3 tip$4) near3 (specimen wafer sample))	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/08/06 13:12
19	19	((((critical adj dimension adj electron adj microscop$2) (CD adj SEM) CDSEM CD-SEM)) and ((tilt$3 angl$3 tip$4) near3 (specimen wafer sample))) and (candidate library database)	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/08/06 13:13
20	13	(((((critical adj dimension adj electron adj microscop$2) (CD adj SEM) CDSEM CD-SEM)) and ((tilt$3 angl$3 tip$4) near3 (specimen wafer sample))) and (candidate library database)) and (cross-section$2 (cross adj section$2))	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/08/06 13:23
21	4	192692.ap.	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/08/06 13:20
22	2	6756590.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/08/06 13:23
-	7772	250/306,307,310,311,397,399.ccls. 356/51,625,635,636,638,639.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/08/06 10:28
-	4137	(250/306,307,310,311,397,399.ccls. 356/51,625,635,636,638,639.ccls.) and (wave (beam near2 (charg$3 electron)))	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/08/06 10:30
-	1561	((250/306,307,310,311,397,399.ccls. 356/51,625,635,636,638,639.ccls.) and (wave (beam near2 (charg$3 electron)))) and intensity	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/08/06 11:04
-	151	(((250/306,307,310,311,397,399.ccls. 356/51,625,635,636,638,639.ccls.) and (wave (beam near2 (charg$3 electron)))) and intensity) and slope	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/08/06 10:33
-	626	(((250/306,307,310,311,397,399.ccls. 356/51,625,635,636,638,639.ccls.) and (wave (beam near2 (charg$3 electron)))) and intensity) and (cross-section$2 (cross adj section$2))	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/08/06 11:05
-	73	((((250/306,307,310,311,397,399.ccls. 356/51,625,635,636,638,639.ccls.) and (wave (beam near2 (charg$3 electron)))) and intensity) and slope) and ((((250/306,307,310,311,397,399.ccls. 356/51,625,635,636,638,639.ccls.) and (wave (beam near2 (charg$3 electron)))) and intensity) and (cross-section$2 (cross adj section$2)))	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/08/06 11:02
-	840	((250/306,307,310,311,397,399.ccls. 356/51,625,635,636,638,639.ccls.) and (wave (beam near2 (charg$3 electron)))) and ((tilt$3 angl$3 tip$4) near3 (specimen wafer sample))	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/08/06 13:12
-	388	(((250/306,307,310,311,397,399.ccls. 356/51,625,635,636,638,639.ccls.) and (wave (beam near2 (charg$3 electron)))) and intensity) and (((250/306,307,310,311,397,399.ccls. 356/51,625,635,636,638,639.ccls.) and (wave (beam near2 (charg$3 electron)))) and ((tilt$3 angl$3 tip$4) near3 (specimen wafer sample)))	USPAT; US-PGPUB; EPO; JPO; DERWENT	2004/08/06 11:05

| - | 190 | (((((250/306,307,310,311,397,399.ccls. 356/51,625,635,636,638,639.ccls.) and (wave (beam near2 (charg$3 electron)))) and intensity) and (((250/306,307,310,311,397,399.ccls. 356/51,625,635,636,638,639.ccls.) and (wave (beam near2 (charg$3 electron)))) and ((tilt$3 angl$3 tip$4) near3 (specimen wafer sample)))) and (cross-section$2 (cross adj section$2)) | USPAT; US-PGPUB; EPO; JPO; DERWENT | 2004/08/06 11:05 |
| - | 27 | (((((250/306,307,310,311,397,399.ccls. 356/51,625,635,636,638,639.ccls.) and (wave (beam near2 (charg$3 electron)))) and intensity) and (((250/306,307,310,311,397,399.ccls. 356/51,625,635,636,638,639.ccls.) and (wave (beam near2 (charg$3 electron)))) and ((tilt$3 angl$3 tip$4) near3 (specimen wafer sample)))) and (cross-section$2 (cross adj section$2))) and (candidate library database) | USPAT; US-PGPUB; EPO; JPO; DERWENT | 2004/08/06 13:13 |

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